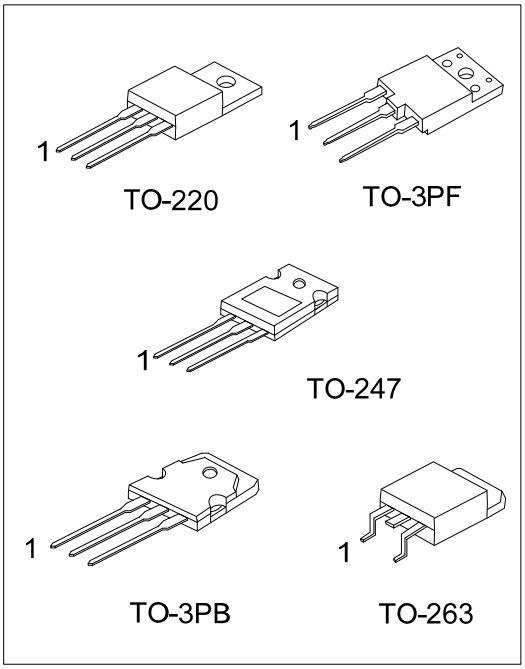
4N150

Power MOSFET

4.0A, 1500V N-CHANNEL POWER MOSFET



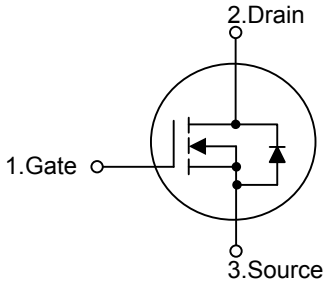
■ DESCRIPTION

The UTC **4N150** is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.

■ FEATURES

* $R_{DS(ON)} \leq 6.5\ \Omega$ @ V_{GS}=10V, I_D=2.0A
* High Switching Speed
* 100% Avalanche Tested

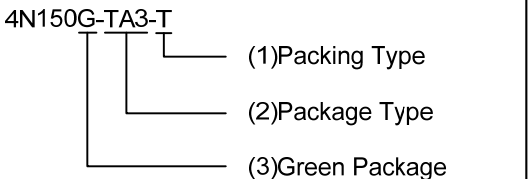
■ SYMBOL



■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
4N150L-TA3-T	4N150G-TA3-T	TO-220	G	D	S	Tube
4N150L-T47-T	4N150G-T47-T	TO-247	G	D	S	Tube
4N150L-TQ2-T	4N150G-TQ2-T	TO-263	G	D	S	Tube
4N150L-TQ2-R	4N150G-TQ2-R	TO-263	G	D	S	Tape Reel
4N150L-T3B-T	4N150G-T3B-T	TO-3PB	G	D	S	Tube
4N150L-T3F-T	4N150G-T3F-T	TO-3PF	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

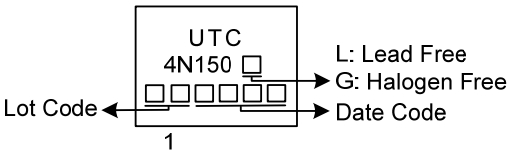


(1) T: Tube, R: Tape Reel

(2) TA3: TO-220, T47: TO-247, TQ2: TO-263
T3B: TO-3PB, T3F: TO-3PF

(3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	1500	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous	I_D	4	A
	Pulsed (Note 2)	I_{DM}	8	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	721	mJ
Peak Diode Recovery dv/dt		dv/dt	2	V/ns
Power Dissipation	TO-220/TO-263	P_D	110	W
	TO-247		140	W
	TO-3PB/TO-3PF		150	W
Junction Temperature		T_J	+150	°C
Storage Temperature		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. L =150mH, I_{AS} = 3.1A, V_{DD} = 90V, R_G = 25Ω, Starting T_J = 25°C
4. I_{SD} ≤ 4A, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C

■ THERMAL DATA

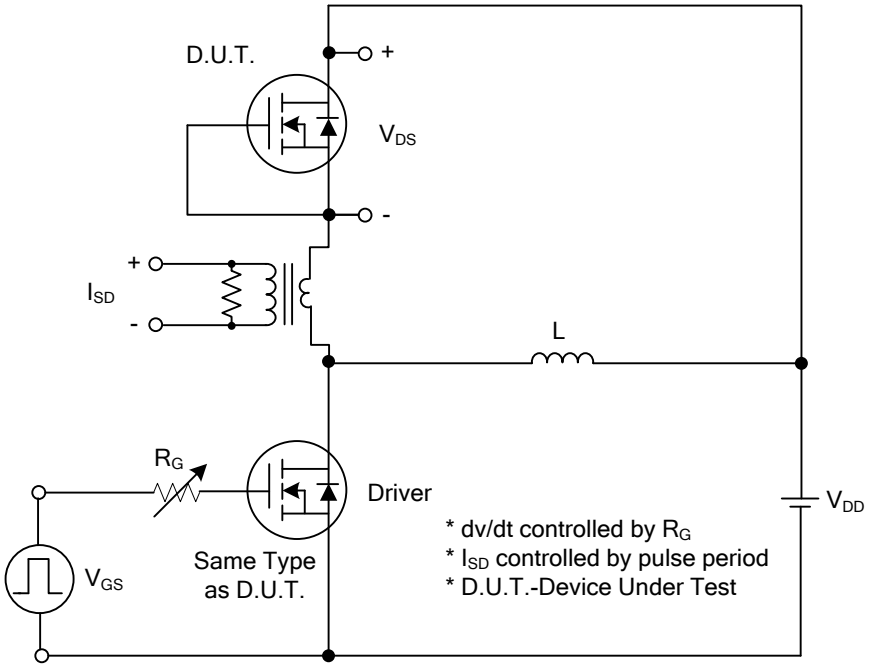
PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220/TO-263	θ_{JA}	62.5	°C/W
	TO-247		50	°C/W
	TO-3PB/TO-3PF		50	°C/W
Junction to Case	TO-220/TO-263	θ_{JC}	1.14	°C/W
	TO-247		0.89	°C/W
	TO-3PB/TO-3PF		0.83	°C/W

■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

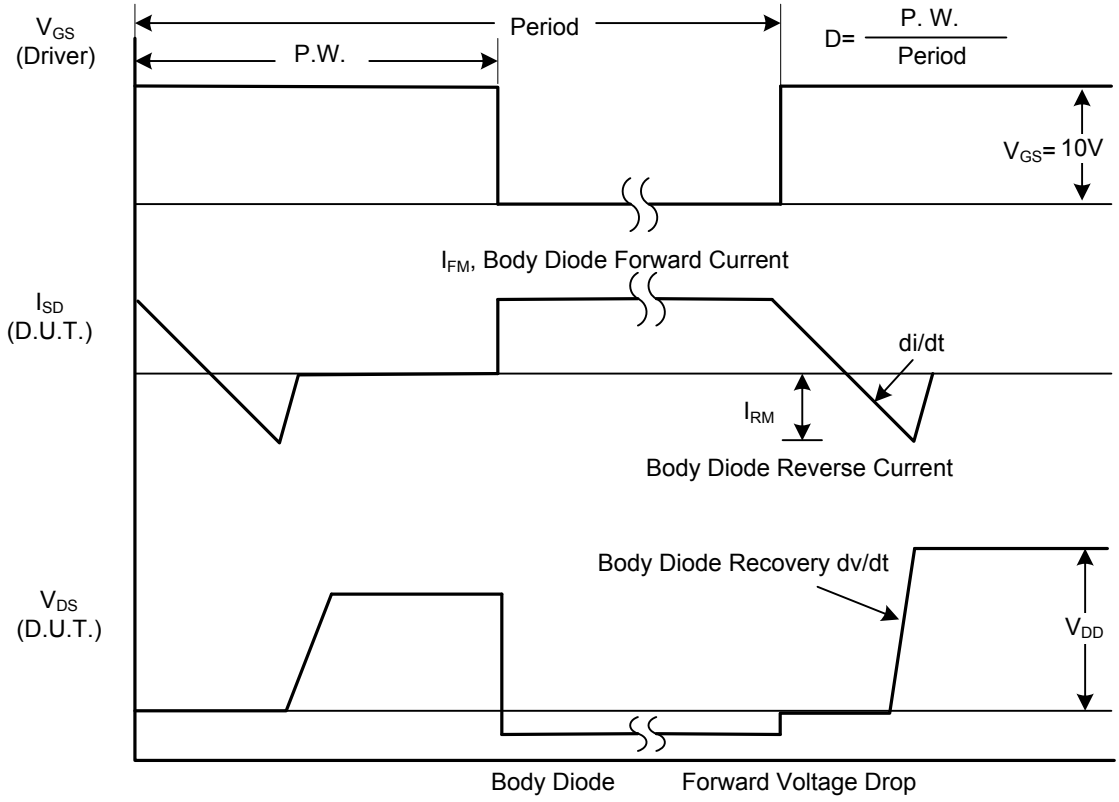
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	I_D=250μA, V_{GS}=0V	1500			V
Drain-Source Leakage Current		I_{DSS}	V_{DS}=1500V, V_{GS}=0V			10	μA
Gate- Source Leakage Current	Forward	I_{GSS}	V_{GS}=+30V, V_{DS}=0V			+100	nA
	Reverse		V_{GS}=-30V, V_{DS}=0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS}=V_{GS}, I_D=250μA	3.0		5.0	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS}=10V, I_D=2.0A			6.5	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}	V_{GS}=0V, V_{DS}=25V, f=1.0MHz		1310		pF
Output Capacitance		C_{OSS}			95		pF
Reverse Transfer Capacitance		C_{RSS}			17		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	V_{DS}=1200V, V_{GS}=10V, I_D=4A I_G=1mA (Note1, 2)		40		nC
Gate to Source Charge		Q_{GS}			11		nC
Gate to Drain Charge		Q_{GD}			16		nC
Turn-ON Delay Time		$t_{D(ON)}$	V_{DS}=100V, V_{GS}=10V, I_D=4A, R_G=25Ω (Note1, 2)		32		ns
Rise Time		t_R			39		ns
Turn-OFF Delay Time		$t_{D(OFF)}$			125		ns
Fall-Time		t_F			47		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I_S				4	A
Maximum Body-Diode Pulsed Current		I_{SM}				8	A
Drain-Source Diode Forward Voltage		V_{SD}	I_S=4A, V_{GS}=0V			1.4	V
Body Diode Reverse Recovery Time		t_{rr}	I_S=4A, V_{GS}=0V, dI_F/dt=100A/μs (Note 1)		1.2		μs
Body Diode Reverse Recovery Charge		Q_{rr}			13.1		μC

Notes: 1. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%.
2. Essentially independent of operating ambient temperature.

■ TEST CIRCUITS AND WAVEFORMS



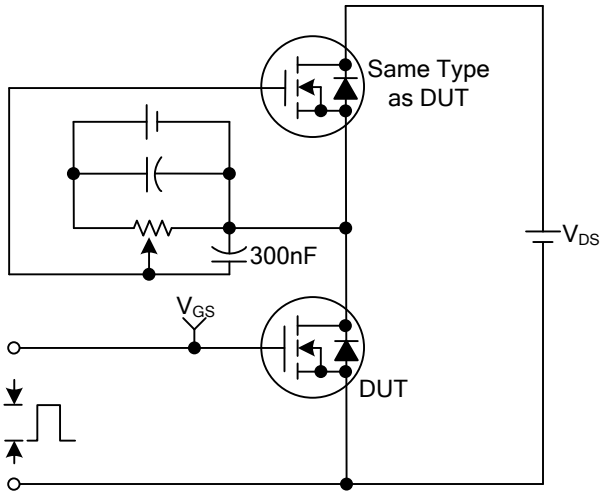
Peak Diode Recovery dv/dt Test Circuit



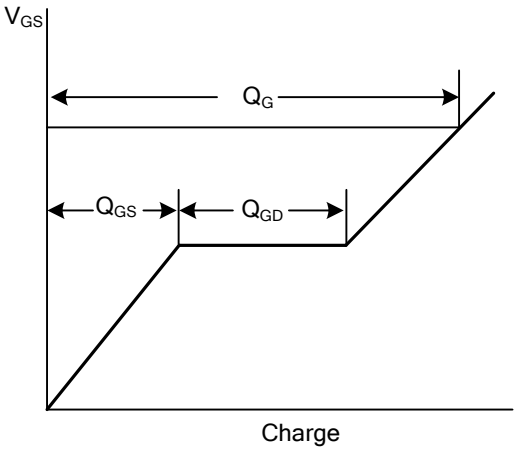
Peak Diode Recovery dv/dt Waveforms

■ TEST CIRCUITS AND WAVEFORMS

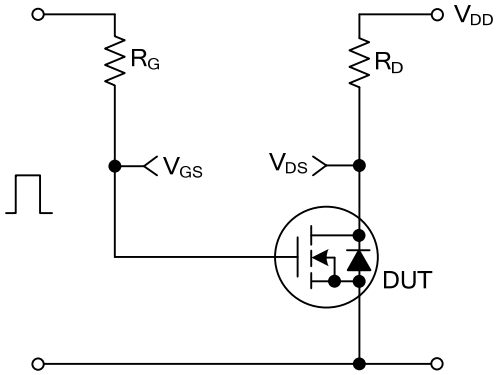
Gate Charge Test Circuit



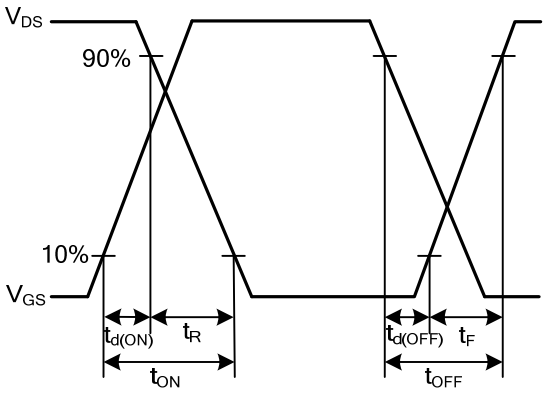
Gate Charge Waveforms



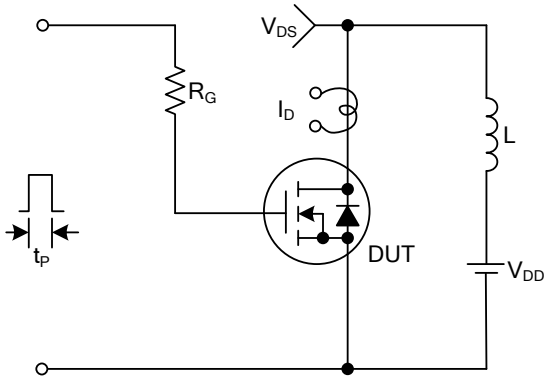
Resistive Switching Test Circuit



Resistive Switching Waveforms

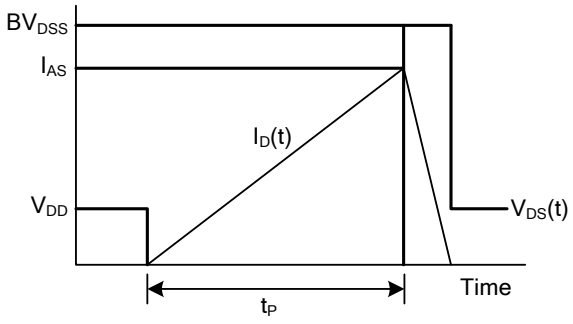


Unclamped Inductive Switching Test Circuit

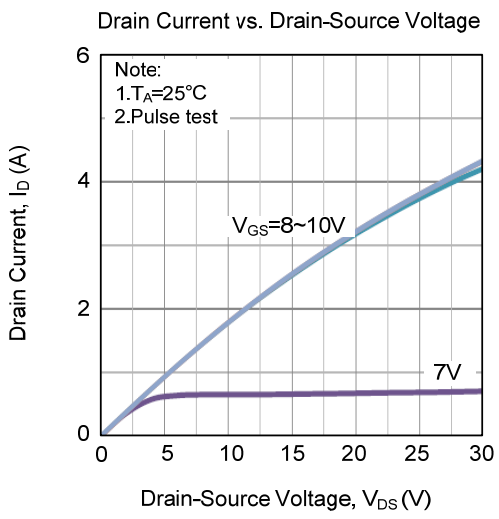


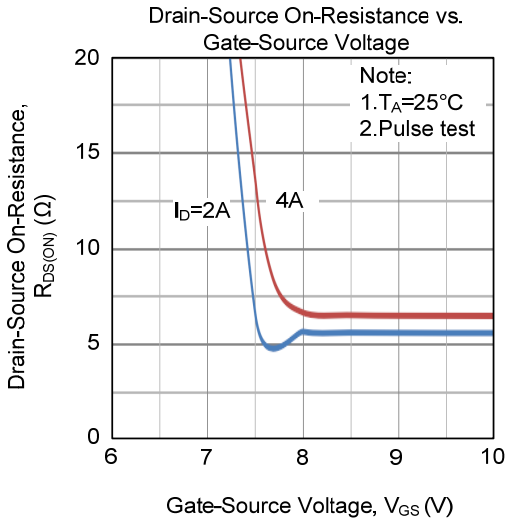
Unclamped Inductive Switching Waveforms

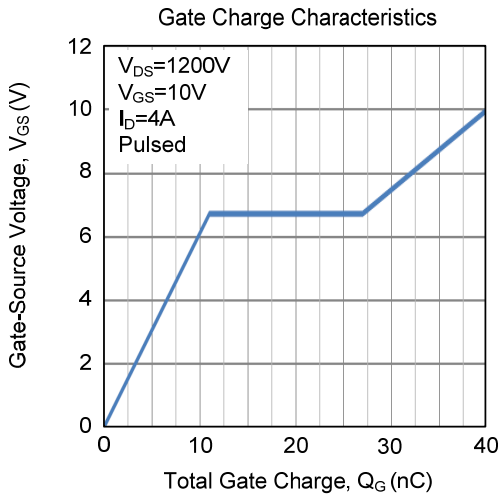
$$E_{AS}=\frac{1}{2}LI_{AS}^2\frac{BV_{DSS}}{BV_{DSS}-V_{DD}}$$

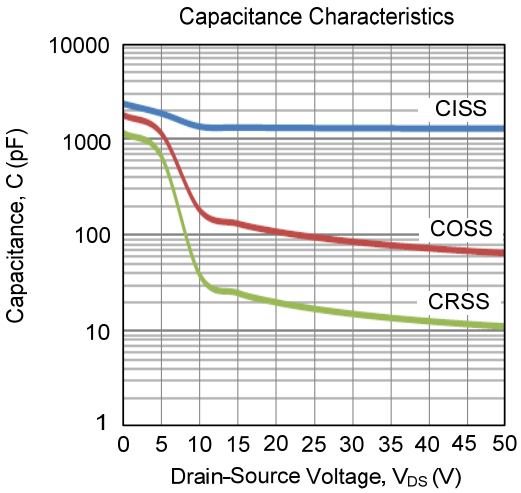


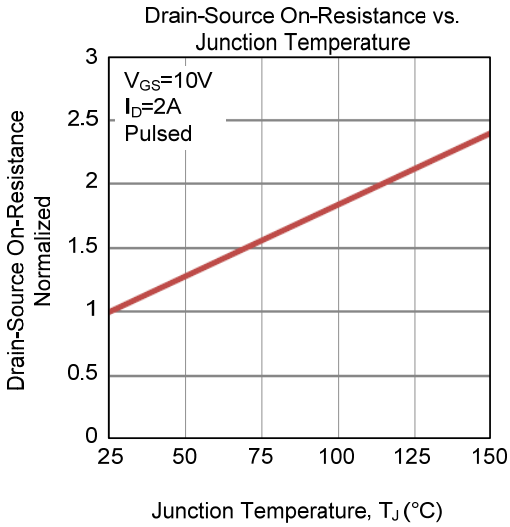
■ TYPICAL CHARACTERISTICS

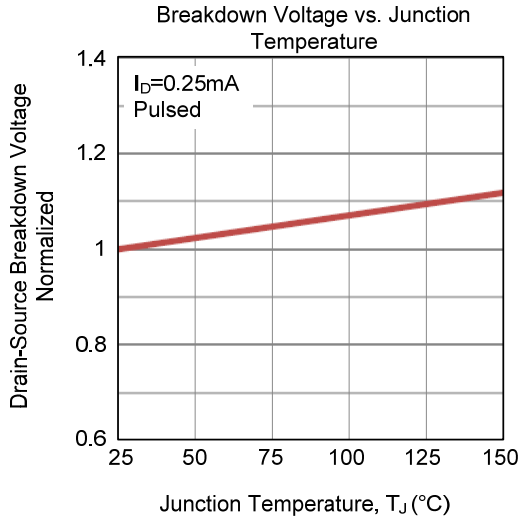




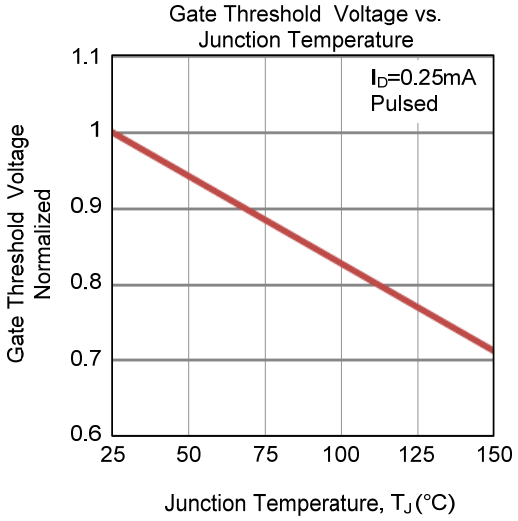


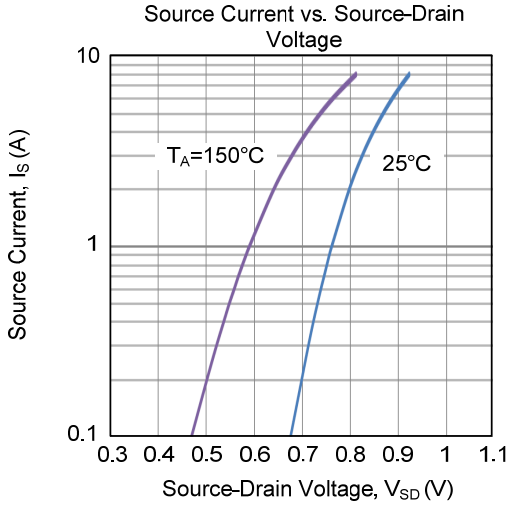


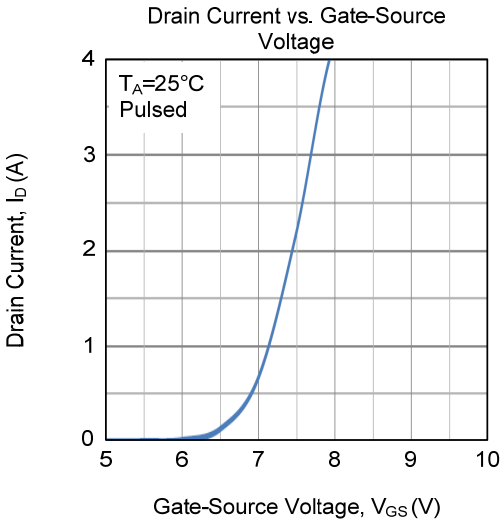


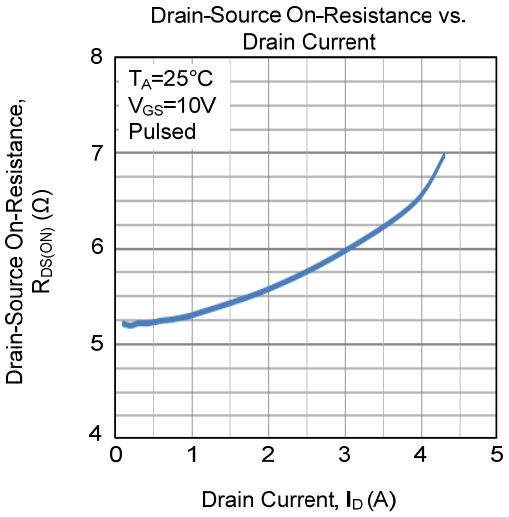


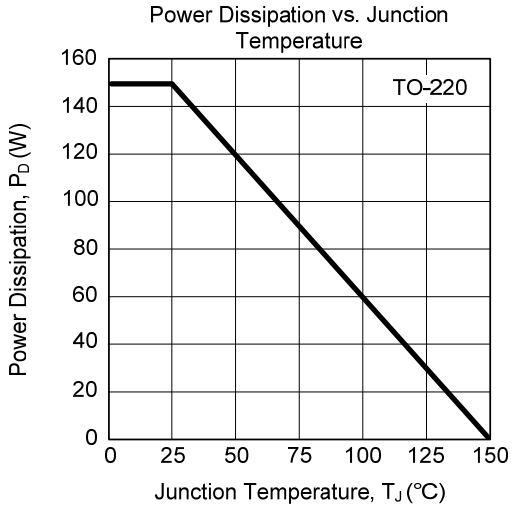
■ TYPICAL CHARACTERISTICS (Cont.)

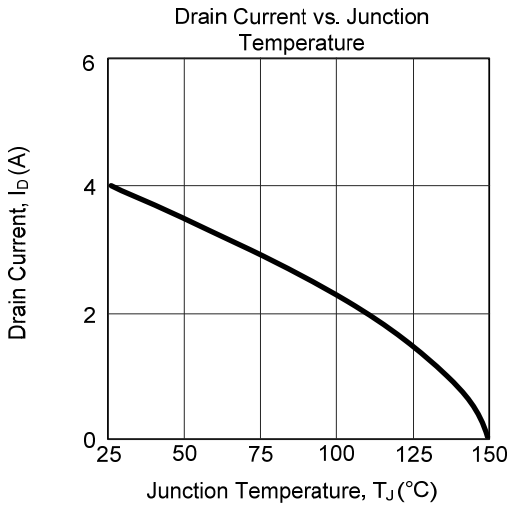












■ TYPICAL CHARACTERISTICS (Cont.)